

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/611,634	AARON, JEFFREY A.	
Examiner		Art Unit		Page 1 of 1
Elmira Mehrmanesh		2113		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,951,611	09-1999	La Pierre, Lee R.	701/29
*	B	US-6,125,458	09-2000	Devan et al.	714/43
*	C	US-5,968,195	10-1999	Ishiyama, Toshio	714/727
*	D	US-5,640,403	06-1997	Ishiyama et al.	714/737
*	E	US-6,128,753	10-2000	Keeble et al.	714/25
*	F	US-4,967,337	10-1990	English et al.	700/79
*	G	US-4,985,857	01-1991	Bajpai et al.	702/184
*	H	US-5,408,412	04-1995	Hogg et al.	701/33
*	I	US-6,052,809	04-2000	Bowden, Kenneth R.	714/738
*	J	US-6,195,773	02-2001	Wada, Shin-ichi	714/724
*	K	US-2002/0078403	06-2002	Gullo et al.	714/37
*	L	US-6,415,395	07-2002	Varma et al.	714/37
*	M	US-2004/0073855	04-2004	Maxwell, Richard	714/724

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.